L Number	Hits	Search Text	DB	Time stamp
-	1148	716/19 -	USPAT;	2004/09/22 11:48
			US-PGPUB;	
		•	ЕРО; ЛРО;	
			DERWENT;	
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i -	758	716/21	USPAT;	2004/09/22 11:48
			US-PGPUB;	
			ЕРО; ЛРО;	
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-	11	(716/19).ccls. and (mask or reticle) and (CAD same ((electron adj beam)	USPAT;	2004/09/22 16:46
		or EB) same data)	US-PGPUB;	
			ЕРО; ЛРО;	
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ا ا	15	(716/21).ccls. and (mask or reticle) and (CAD same ((electron adj beam)	USPAT;	2004/09/22 13:30
		or EB) same data)	US-PGPUB;	200 1107/22 13:30
'		or EB) barro data)	ЕРО; ЛРО;	
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_	1	(716/21).ccls. and (mask or reticle) and (CAD same ((electron adj beam)	_	2004/09/22 13:33
-	1	or EB) same data) and (inspect\$ adj data)	USPAT;	2004/09/22 13:33
		of ED) same data) and (hispects adjuata)	US-PGPUB;	
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-	2	(716/\$).ccls. and (mask or reticle) and (CAD same ((electron adj beam)	USPAT;	2004/09/22 13:34
		or EB) same data) and (inspect\$ adj data)	US-PGPUB;	
1			ЕРО; ЛРО;	
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		() () () () () () () () () ()	IBM_TDB	
-	13	(mask or reticle) and (CAD same ((electron adj beam) or EB) same	USPAT;	2004/09/22 13:35
		data) and (inspect\$ adj data)	US-PGPUB;	
			ЕРО; ЛРО;	
		•	DERWENT;	
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-	2	(mask or reticle) and (CAD same ((electron adj beam) or EB) same	USPAT;	2004/09/22 17:11
		data) and ((data adj conversion) adj error)	US-PGPUB;	
			ЕРО; ЈРО;	
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-	2	(mask or reticle) and (((electron adj beam) or EB) same data) and ((data	USPAT;	2004/09/22 17:13
		adj conversion) adj error)	US-PGPUB;	
			ЕРО; ЛРО;	
i l			DERWENT;	
			IBM_TDB	,
-	3	(mask or reticle) and ((data adj conversion) adj error)	USPAT;	2004/09/22 17:20
			US-PGPUB;	
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		,	IBM_TDB	
-	3	(mask or reticle) and ((data adj (translation or conversion) adj error))	USPAT;	2004/09/22 18:26
		, , , , , , , , , , , , , , , , , , ,	US-PGPUB;	
i	,		ЕРО; ЛРО;	
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_	2	(mask or reticle) and CAD and ((data adj (translation or conversion) adj	USPAT;	2004/09/22 18:27
l	~	error))	US-PGPUB;	2007107122 10.27
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-	2	(mask or reticle) and CAD and ((data adj (translation or conversion) adj	USPAT;	2004/09/22 18:29
		(error or mistake)))	US-PGPUB;	
İ		·	ЕРО; ЈРО;	
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-	2	CAD and ((data adj (translation or conversion) adj (error or mistake)))	USPĀT;	2004/09/22 18:30
			US-PGPUB;	
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_	0	(beam adj lithograph) same (inspection adj method)	USPAT;	2004/09/23 10:49
-	"	(ocani adj hdiographi) same (hispection adj method)	US-PGPUB,	2004/03/23 10.43
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1			ЕРО; ЛРО;	
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-	0	(beam adj lithograph) and (inspection adj method)	USPAT;	2004/09/23 10:47
			US-PGPUB;	
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-	7	(beam adj lithography) same (inspection adj method)	USPĀT;	2004/09/23 10:50
		, , , , , , , , , , , , , , , , , , , ,	US-PGPUB;	
	*	•	ЕРО; ЈРО;	
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_	. 30	(beam adj lithography) and (inspection adj method)	USPAT;	2004/09/23 12:38
]	(ocan ad natography) and (inspection ad incline)	US-PGPUB;	2004/03/23 12.36
			ЕРО; ЛРО;	
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	21		IBM_TDB	
-	21	(beam adj lithography) and (inspection adj method) and (quality or	USPAT;	2004/09/23 12:40
		contrast)	US-PGPUB;	
			ЕРО; ЈРО;	
			DERWENT;	
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-	2	(beam adj lithography) and ((inspection adj method) same (quality or	USPAT;	2004/09/23 12:42
İ		contrast))	US-PGPUB;	
			ЕРО; ЈРО;	
			DERWENT;	
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[-	1	(mask or reticle) and ((data adj verification) same (coordinate adj data))	USPĀT;	2004/09/27 13:18
			US-PGPUB;	
			ЕРО; ЛРО;	
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_	4	(mask or reticle) and ((data adj verification) same (coordinate))	USPAT;	2004/09/27 13:36
	, I	(continue))	US-PGPUB;	2007107121 13.3U
			EPO; ЛРО;	
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	38	(magk or ratials) and ((data adi (abashe	IBM_TDB	2004/00/27 12 52
-	38	(mask or reticle) and ((data adj (check\$ or verification)) same	USPAT;	2004/09/27 13:52
		(coordinate))	US-PGPUB;	
		•	ЕРО; ЛРО;	
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	_		IBM_TDB	
-	9	(mask or reticle) and (electron adj beam) and ((data adj (check\$ or	USPAT;	2004/09/27 14:02
		verification)) same (coordinate))	US-PGPUB;	•
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1			2004/09/27 14:29
	verification)) same ((two adj dimension\$) adj (coordinate)))	US-PGPUB;	
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0	(mask or reticle) and (electron adj beam) and ((pattern adj (check\$ or	USPAT;	2004/09/27 14:30
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